

Data sheet acquired from Harris Semiconductor

SCHS187C

#### January 1998 - Revised July 2003

# CD54/74HC533, CD54/74HCT533, CD54/74HC563, CD74HCT563

### **High-Speed CMOS Logic Octal Inverting Transparent Latch, Three-State Outputs**

#### Features

- Common Latch-Enable Control
- Common Three-State Output Enable Control
- Buffered Inputs
- · Three-State Outputs
- . Bus Line Driving Capacity
- Typical Propagation Delay = 13ns at V<sub>CC</sub> = 5V,  $C_L = 15pF$ ,  $T_A = 25^{\circ}C$  (Data to Output)
- Fanout (Over Temperature Range)
  - Standard Outputs........... 10 LSTTL Loads
  - Bus Driver Outputs ........... 15 LSTTL Loads
- Wide Operating Temperature Range . . . -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
  - 2V to 6V Operation
  - High Noise Immunity: N<sub>IL</sub> = 30%, N<sub>IH</sub> = 30% of V<sub>CC</sub> at  $V_{CC} = 5V$
- HCT Types
  - 4.5V to 5.5V Operation
  - Direct LSTTL Input Logic Compatibility,  $V_{IL} = 0.8V (Max), V_{IH} = 2V (Min)$
  - CMOS Input Compatibility,  $I_I \le 1 \mu A$  at  $V_{OI}$ ,  $V_{OH}$

### Description

The 'HC533, 'HCT533, 'HC563, and CD74HCT563 are high-speed Octal Transparent Latches manufactured with silicon gate CMOS technology. They possess the low power consumption of standard CMOS integrated circuits, as well as the ability to drive 15 LSTTL devices.

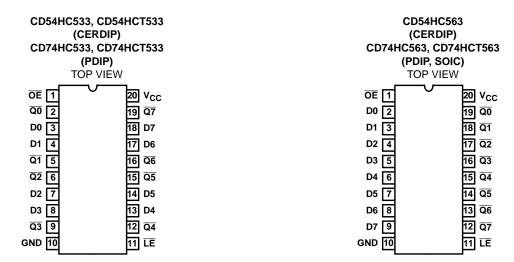
The outputs are transparent to the inputs when the latch enable  $(\overline{LE})$  is high. When the latch enable  $(\overline{LE})$  goes low the data is latched. The output enable  $(\overline{OE})$  controls the three-state outputs. When the output enable  $(\overline{OE})$  is high the outputs are in the high impedance state. The latch operation is independent of the state of the output enable.

The 'HC533 and 'HCT533 are identical in function to the 'HC563 and CD74HCT563 but have different pinouts. The 'HC533 and 'HCT533 are similar to the 'HC373 and 'HCT373; the latter are non-inverting types.

#### Ordering Information

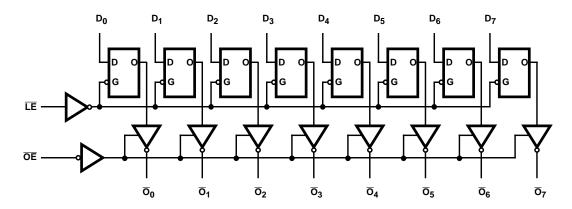
PART NUMBER	TEMP. RANGE ( <sup>O</sup> C)	PACKAGE
CD54HC533F3A	-55 to 125	20 Ld CERDIP
CD54HC563F3A	-55 to 125	20 Ld CERDIP
CD54HCT533F3A	-55 to 125	20 Ld CERDIP
CD74HC533E	-55 to 125	20 Ld PDIP
CD74HC563E	-55 to 125	20 Ld PDIP
CD74HC563M	-55 to 125	20 Ld SOIC
CD74HCT533E	-55 to 125	20 Ld PDIP
CD74HCT563E	-55 to 125	20 Ld PDIP
CD74HCT563M	-55 to 125	20 Ld SOIC

#### **Pinouts**



### Functional Block Diagram

#### HC/HCT533



TRUTH TABLE

OUTPUT ENABLE	LATCH ENABLE	DATA	Q OUTPUT
L	Н	Н	L
L	Н	L	Н
L	L	I	Н
L	L	h	L
Н	X	X	Z

H = High Voltage Level, L = Low Voltage Level, X = Don't Care, Z = High Impedance State, I = Low voltage level one set-up time prior to the high to low latch enable transition, h = High voltage level one set-up time prior to the high to low latch enable transition.

### **Absolute Maximum Ratings**

DC Supply Voltage, V <sub>CC</sub> 0.5V to 7V
DC Input Diode Current, I <sub>IK</sub>
For $V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$
DC Output Diode Current, I <sub>OK</sub>
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$ ±20mA
DC Drain Current, per Output, IO
For -0.5V < V <sub>O</sub> < V <sub>CC</sub> + 0.5V±35mA
DC Output Source or Sink Current per Output Pin, IO
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$ ±25mA
DC V <sub>CC</sub> or Ground Current, I <sub>CC</sub>

#### **Thermal Information**

Thermal Resistance (Typical, Note 1)	$\theta_{JA}$ (oC/W)
E (PDIP) Package	69
M (SOIC) Package	
Maximum Junction Temperature	
Maximum Storage Temperature Range	65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300 <sup>o</sup> C
(SOIC - Lead Tips Only)	

### **Operating Conditions**

Temperature Range, $T_A$ 55 $^{0}$ C to 125 $^{0}$ C Supply Voltage Range, $V_{CC}$
HC Types2V to 6V
HCT Types
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub> 0V to V <sub>CC</sub>
Input Rise and Fall Time
2V
4.5V 500ns (Max)
6V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTE:

1. The package thermal impedance is calculated in accordance with JESD 51-7.

### **DC Electrical Specifications**

			TEST CONDITIONS		25°C			-40°C T	O 85°C	-55°C TO 125°C		
PARAMETER	SYMBOL	V <sub>I</sub> (V)	I <sub>O</sub> (mA)	V <sub>CC</sub> (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES												
High Level Input	V <sub>IH</sub>	-	-	2	1.5	-	-	1.5	-	1.5	-	V
Voltage				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input	V <sub>IL</sub>	-	-	2	-	-	0.5	-	0.5	-	0.5	V
Voltage				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output	V <sub>OH</sub>	V <sub>IH</sub> or	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
Voltage CMOS Loads		V <sub>IL</sub>	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output	1		-6	4.5	3.98	-	-	3.84	-	3.7	-	V
Voltage TTL Loads			-7.8	6	5.48	1	1	5.34	-	5.2	-	V
Low Level Output	V <sub>OL</sub>	V <sub>IH</sub> or	0.02	2	-	-	0.1	-	0.1	-	0.1	V
Voltage CMOS Loads		V <sub>IL</sub>	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
000 20000			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output	1		6	4.5	-	-	0.26	-	0.33	-	0.4	V
Voltage TTL Loads			7.8	6	-	-	0.26	Ī	0.33	-	0.4	V
Input Leakage Current	Ι <sub>Ι</sub>	V <sub>CC</sub> or GND	-	6	-	-	±0.1	-	±1	-	±1	μА
Quiescent Device Current	Icc	V <sub>CC</sub> or GND	0	6	-		8	-	80	-	160	μА

### DC Electrical Specifications (Continued)

		TEST CONDITIONS				25°C		-40°C TO 85°C		-55°C TO 125°C		
PARAMETER	SYMBOL	V <sub>I</sub> (V)	I <sub>O</sub> (mA)	V <sub>CC</sub> (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
Three-State Leakage Current	-	V <sub>IL</sub> or V <sub>IH</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	6	-	-	±0.5	-	±5	-	±10	μА
HCT TYPES			•	•							-	•
High Level Input Voltage	V <sub>IH</sub>	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V <sub>IL</sub>	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V <sub>ОН</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	lį	V <sub>CC</sub> to GND	-	5.5	-	-	±0.1	-	±1	-	±1	μА
Quiescent Device Current	Icc	V <sub>CC</sub> or GND	0	5.5	-	-	8	-	80	-	160	μА
Three-State Leakage Current	-	V <sub>IL</sub> or V <sub>IH</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	5.5	-	-	±0.5	-	±5	-	±10	μА
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI <sub>CC</sub> (Note 2)	V <sub>CC</sub> -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μА

#### NOTE:

#### **HCT Input Loading Table**

INPUT	UNIT LOADS
D0 - D7	0.15
<u>LE</u>	0.30
ŌĒ	0.55

NOTE: Unit Load is  $\Delta I_{CC}$  limit specified in DC Electrical Specifications table, e.g., 360 $\mu A$  max at  $25^{o}C.$ 

<sup>2.</sup> For dual-supply systems theoretical worst case ( $V_I = 2.4V$ ,  $V_{CC} = 5.5V$ ) specification is 1.8mA.

### **Prerequisite For Switching Specifications**

		TEST	V <sub>CC</sub>		25°C		-40°C T	O 85°C	-55°C TO 125°C		
PARAMETER	SYMBOL	CONDITIONS	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES	_						-				
LE Pulse Width	t <sub>W</sub>	-	2	80	-	-	100	-	120	-	ns
			4.5	16	-	-	20	-	24	-	ns
			6	14	-	-	17	-	20	-	ns
Set-up Time Data to LE	t <sub>SU</sub>	-	2	50	-	-	65	-	75	-	ns
			4.5	10	-	-	13	-	15	-	ns
			6	9	-	-	11	-	13	-	ns
Hold Time, Data to LE	t <sub>H</sub>	-	2	35	-	-	45	-	55	-	ns
(533)			4.5	7	-	-	9	-	11	-	ns
			6	6	-	-	8	-	7	-	ns
Hold Time, Data to LE	t <sub>H</sub>	-	2	4	-	-	4	-	4	-	ns
(563)			4.5	4	-	-	4	-	4	-	ns
			6	4	-	-	4	-	4	-	ns
HCT TYPES		•							•		
LE Pulse Width	t <sub>w</sub>	-	4.5	16	-	-	20	-	24	-	ns
Set-up Time Data to LE	t <sub>w</sub>	-	4.5	10	-	-	13	-	15	-	ns
Hold Time, Data to LE (533)	t <sub>H</sub>	-	4.5	8	-	-	10	-	12	-	ns
Hold Time, Data to LE (563)	t <sub>H</sub>	-	4.5	5	-	-	5	-	5	-	ns

### **Switching Specifications** Input $t_p$ , $t_f = 6ns$

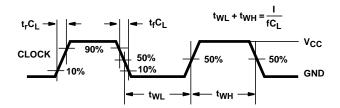
		TEST		25°C		-40°C TO 85°C	-55°C TO 125°C	
PARAMETER	SYMBOL	CONDITIONS	V <sub>CC</sub> (V)	TYP	MAX	MAX	MAX	UNITS
HC TYPES								
Propagation Delay,	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	165	205	250	ns
Data to Qn (HC533)			4.5	-	33	41	50	ns
			6	-	28	35	43	ns
		C <sub>L</sub> = 15pF	5	13	-	-	-	ns
Propagation Delay,	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	150	190	225	ns
Data to Qn (HC563)			4.5	-	30	38	45	ns
(,			6	-	26	33	38	ns
		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
Propagation Delay,	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	175	220	265	ns
LE to Qn (HC533)			4.5	-	35	44	53	ns
(,			6	-	30	37	45	ns
		C <sub>L</sub> = 15pF	5	14	-	-	-	ns
Propagation Delay,	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	165	205	250	ns
LE to Qn (HC563)			4.5	-	33	41	50	ns
			6	-	28	35	43	ns
		C <sub>L</sub> = 15pF	5	13	-	-	-	ns

### Switching Specifications Input $t_r$ , $t_f = 6ns$ (Continued)

		TEST		25	°c	-40°C TO 85°C	-55°C TO 125°C	
PARAMETER	SYMBOL	CONDITIONS	V <sub>CC</sub> (V)	TYP	MAX	MAX	MAX	UNITS
Enable Times	t <sub>PZH</sub> , t <sub>PZL</sub>	C <sub>L</sub> = 50pF	2	-	150	190	225	ns
(HC533)			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
Disable Times	t <sub>PHZ</sub> , t <sub>PLZ</sub>	C <sub>L</sub> = 50pF	2	-	150	190	225	ns
(HC533)			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
Enable and Disable Times	t <sub>PZH</sub> , t <sub>PZL</sub> ,	C <sub>L</sub> = 50pF	2	-	150	190	225	ns
HC563)	t <sub>PHZ</sub> , t <sub>PLZ</sub>		4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
Input Capacitance	Cl	-	-	-	10	10	10	pF
Three-State Output Capacitance	CO	-	-	-	20	20	20	pF
Power Dissipation Capacitance (Notes 3, 4)	C <sub>PD</sub>	-	5	42	-	-	-	pF
HCT TYPES								
Propagation Delay, Data to Qn	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	4.5	-	34	43	51	ns
(HC/HCT533)		C <sub>L</sub> = 15pF	5	14	-	-	-	ns
Propagation Delay,	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	4.5	-	30	38	45	ns
Data to Qn (HC/HCT563)		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
Propagation Delay,	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	4.5	ı	38	48	57	ns
LE to Qn (HC/HCT533)		C <sub>L</sub> = 15pF	5	16	-	-	-	ns
Propagation Delay,	t <sub>PZL</sub> , t <sub>PZH</sub>	C <sub>L</sub> = 50pF	4.5	-	35	44	53	ns
LE to Qn (HC/HCT563)		C <sub>L</sub> = 15pF	5	14	-	-	-	ns
Enable Times	t <sub>PLZ</sub> , t <sub>PZH</sub>	C <sub>L</sub> = 50pF	4.5	-	35	44	53	ns
(HC/HCT533)		C <sub>L</sub> = 15pF	5	14	-	-	-	ns
Disable Times	t <sub>TLH</sub> , t <sub>THL</sub>	C <sub>L</sub> = 50pF	4.5	-	30	38	45	ns
(HC/HCT533)		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
Enable and Disable Times	t <sub>PZH</sub> , t <sub>PZL</sub> ,	C <sub>L</sub> = 50pF	4.5	-	35	44	53	ns
(HC/HCT563)	t <sub>PHZ</sub> , t <sub>PLZ</sub>	C <sub>L</sub> = 15pF	5	14	-	-	-	ns
Input Capacitance	C <sub>I</sub>	-	-	-	10	10	10	pF
Power Dissipation Capacitance (Notes 3, 4)	C <sub>PD</sub>	-	5	42	-	-	-	pF

- 3.  $\ensuremath{\text{C}_{\text{PD}}}$  is used to determine the no-load dynamic power consumption, per latch.
- 4. P<sub>D</sub> (total power per latch) = C<sub>PD</sub> V<sub>CC</sub><sup>2</sup> f<sub>i</sub> + Σ C<sub>L</sub> V<sub>CC</sub><sup>2</sup> f<sub>o</sub> where f<sub>i</sub> = Input Frequency, f<sub>o</sub> = Output Frequency, C<sub>L</sub> = Output Load Capacitance, V<sub>CC</sub> = Supply Voltage.

#### Test Circuits and Waveforms



NOTE: Outputs should be switching from 10% V $_{CC}$  to 90% V $_{CC}$  in accordance with device truth table. For f $_{MAX}$ , input duty cycle = 50%.

FIGURE 1. HC CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

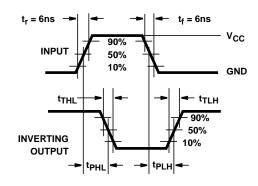


FIGURE 3. HC TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

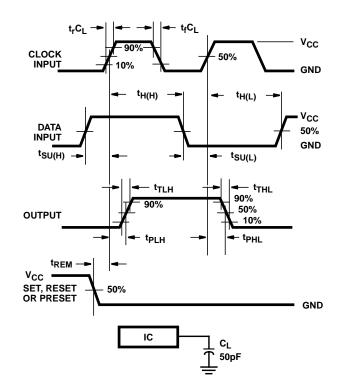
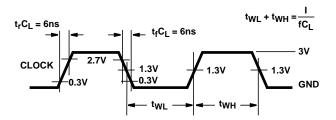


FIGURE 5. HC SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS



NOTE: Outputs should be switching from 10%  $V_{CC}$  to 90%  $V_{CC}$  in accordance with device truth table. For  $f_{MAX}$ , input duty cycle = 50%.

FIGURE 2. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

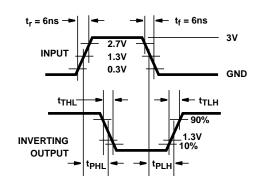


FIGURE 4. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

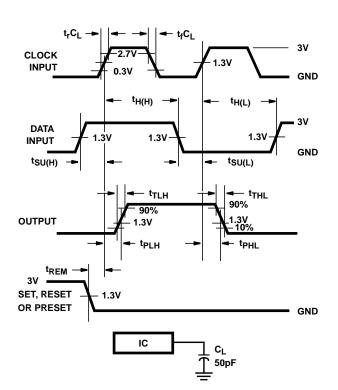
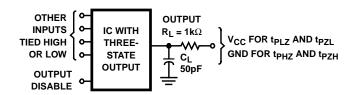


FIGURE 6. HCT SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

#### Test Circuits and Waveforms (Continued) – 6ns 6ns 3V V<sub>CC</sub> OUTPUT OUTPUT 90% **DISABLE** 50% DISABLE 10% 0.3 GND GND t<sub>PZL</sub> → - t<sub>PLZ</sub> → t<sub>PZL</sub> ► t<sub>PLZ</sub> → **OUTPUT LOW** OUTPUT LOW 50% TO OFF TO OFF 1.3V 10% 10% ◆ t<sub>PHZ</sub> ◆ - t<sub>PZH</sub> · ◆ t<sub>PHZ</sub> → tpzh -90% 90% **OUTPUT HIGH OUTPUT HIGH** 50% TO OFF TO OFF 1.3V OUTPUTS **OUTPUTS OUTPUTS OUTPUTS OUTPUTS OUTPUTS ENABLED** ENABLED **DISABLED ENABLED** DISABLED **ENABLED**

FIGURE 7. HC THREE-STATE PROPAGATION DELAY WAVEFORM

FIGURE 8. HCT THREE-STATE PROPAGATION DELAY WAVEFORM



NOTE: Open drain waveforms  $t_{PLZ}$  and  $t_{PZL}$  are the same as those for three-state shown on the left. The test circuit is Output  $R_L = 1k\Omega$  to  $V_{CC}$ ,  $C_L = 50pF$ .

FIGURE 9. HC AND HCT THREE-STATE PROPAGATION DELAY TEST CIRCUIT





24-Aug-2018

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
5962-8606201RA	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8606201RA CD54HC563F3A	Samples
5962-8681301RA	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8681301RA CD54HC533F3A	Samples
CD54HC533F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8681301RA CD54HC533F3A	Samples
CD54HC563F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8606201RA CD54HC563F3A	Samples
CD54HCT533F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD54HCT533F3A	Samples
CD74HC533E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC533E	Samples
CD74HC563E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC563E	Samples
CD74HCT533E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT533E	Samples
CD74HCT563E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT563E	Samples
CD74HCT563M	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT563M	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.





24-Aug-2018

- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF CD54HC533, CD54HC563, CD54HCT533, CD74HC533, CD74HC563, CD74HC5533:

- Catalog: CD74HC533, CD74HC563, CD74HCT533
- Military: CD54HC533, CD54HC563, CD54HCT533

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

### 14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

### N (R-PDIP-T\*\*)

### PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOIC



- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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